

Two Day Workshop on Bio-XFEL Data Analysis



August 21 - 22, 2014

at the

Lawrence Berkeley National Lab, California



Application Deadline June 13, 2014

We are pleased to announce the first Workshop on Bio-XFEL Data Analysis, organized as a collaborative effort between the NSF BioXFEL Science and Technology Center, and the Physical Biosciences Division of Lawrence Berkeley National Laboratory.

Serial crystallography is a rapidly growing field with a correspondingly rapidly growing user base. One of the main bottlenecks in serial crystallography is the ability to rapidly filter and analyze large datasets to arrive at accurate structure factors for structure solution and refinement. This workshop is designed as an introduction to serial crystallography analysis tools, and discussion of how to recognize and address data processing challenges and assess the data quality compared to 'normal' synchrotron crystallography.

Day 1 will consist of lecture sessions covering an introduction to serial (femtosecond) crystallography (SFX), software suites available for SFX data analysis and key issues in data processing and assessment of SFX data quality.

Day 2 will involve hands-on computer tutorials and live demonstrations covering the software presented on day 1. These computer lab sessions are limited to 30 participants. The tutorials will be run by the software developers with a team of expert users. LCLS will be providing computing facilities.

Some travels funds available for students. See the website below for an application.

Speakers and Instructors

Paul Adams, *LBNL*
Anton Barty, *CFEL, DESY*
Wolfgang Brehm, *Uni Konstanz*
Aaron Brewster, *LBNL*
Johan Hattne, *HHMI*
James Holton, *LBNL*

Karol Nass, *Max Planck
Institute for Medical Research*
Nick Sauter, *LBNL*
Thomas White, *CFEL, DESY*
Nadia Zatsepin, *ASU*
Oliver Zeldin, *Stanford*



For more information: www.bioxfel.org/events/details/9